Wire-wound Metal Power Inductors MCOIL<sup>™</sup> LSBH series

for General Electronic Equipment for Consumer

Wire-wound Metal Power Inductors MCOIL<sup>™</sup> LSBH series (125°C guaranteed product)

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Wire-wound Metal Power Inductors MCOIL<sup>™</sup> LLBH series

for Medical Devices classified as GHTF Classes A or B (Japan Classes I or II)

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for Medical Devices classified as GHTF Classes A or B (Japan Classes I or II)

## RELIABILITY DATA

1. Operating Tempe	1. Operating Temperature Range		
Specified Value	$-40 \sim +105^{\circ}C:LSBH/LLBH$ $-40 \sim +125^{\circ}C:LSBH/LLBH (125^{\circ}C)$ guaranteed product)		
Test Methods and Remarks	Including self-generated heat		

## 2. Storage Temperature Range

2. Otoruge Tempera			
Specified Value	-40~+85°C		
Test Methods and Remarks	0 to 40°C for the product with taping.		

3. Rated current			
	Specified Value	Within the specified tolerance	

4. Inductance			
Specified Value	Within the specified tolerance		
Test Methods and Remarks	Measuring equipment Measuring frequency	: LCR Meter(HP 4285A or equivalent) : 1MHz、1V	

5. DC Resistance		
Specified Value	Vithin the specified tolerance	
Test Methods and Remarks	Measuring equipment : DC ohmmeter (HIOKI 3227 or equivalent)	

6. Self resonance frequency	
Specified Value	

7. Temperature ch	7. Temperature characteristic		
Specified Value	e Inductance change : Within ±15%		
Test Methods and Remarks	LSBH/LLBH: Measurement of inductance shall be taken at temperature range within $-40^{\circ}C \sim +105^{\circ}C$ . With reference to inductance value at $+20^{\circ}C$ ., change rate shall be calculated. LSBH/LLBH (125°C guaranteed product): Measurement of inductance shall be taken at temperature range within $-40^{\circ}C \sim +125^{\circ}C$ . With reference to inductance value at $+20^{\circ}C$ ., change rate shall be calculated.		



8. Resistance to fle	xure of substrate		
Specified Value	No damage		
Test Methods and Remarks	The test samples shall be s until deflection of the test Test board size Test board material Solder cream thickness	-	ustrated below, apply force in the direction of the arrow indicating Force Rod $10 \xrightarrow{20}$ Board R5 $45\pm 2mm$ $45\pm 2mm$

9. Insulation resistance : between wires
Specified Value -

10. Insulation resistance : between wire and core		
Specified Value	LSBH/LLBH: DC25V 100kΩ min LSBH/LLBH (125°C guaranteed product): DC50V 100kΩ min	

## 11. Withstanding voltage : between wire and core Specified Value

12. Adhesion of terr	12. Adhesion of terminal electrode		
Specified Value	No abnormality.		
	The test samples shall be s	oldered to the test board by the reflow.	
Test Methods and Applied force : 10N (1608 type: 5N) to X and Y directions.			
Remarks	Duration	: 5s.	
	Solder cream thickness	: 0.1mm.	

13. Resistance to vibration					
Specified Value	Inductance change : Within $\pm 10\%$ No significant abnormality in appearance.				
	The test samples shall be Then it shall be submitted	soldered to the test board by the reflow. to below test conditions.			
	Frequency Range	10~55Hz			
Test Methods	Total Amplitude	1.5mm (May not exceed acceleration 196m/s <sup>2</sup> )			
and Remarks	Sweeping Method	10Hz to 55Hz to 10Hz for 1min.			
	Time	X       Y     For 2 hours on each X, Y, and Z axis.       Z			
	Recovery : At least 2hrs of recovery under the standard condition after the test, followed by the measurement within 48hrs.				

14. Solderability			
Specified Value	At least 90% of surface of terminal electrode is covered by new solder.		
Test Methods and Remarks	The test samples shall be Flux : Ethanol solution cor Solder Temperature Immersing speed Time XImmersion depth : All si	245±5°C           25mm/s           5±0.5 sec.	nen immersed in molten solder as shown in below table.

15. Resistance to s	oldering heat
Specified Value	Inductance change : Within $\pm 10\%$ No significant abnormality in appearance.
Test Methods and Remarks	The test sample shall be exposed to reflow oven at $230^{\circ}$ C for 40 seconds, with peak temperature at $260+0/-5^{\circ}$ C for 5 seconds, 3 times. Test board material : Glass epoxy-resin Test board thickness : 1.0mm Recovery : At least 2hrs of recovery under the standard condition after the test, followed by the measurement within 48hrs.

16. Thermal shock									
Specified Value	Inductance change : Within $\pm 10\%$								
opecified value	No signifi	No significant abnormality in appearance.							
	LSBH/LL	.BH:			LSBH/LLBH (125°C guaranteed product):				
	The test	samples shall be soldered	to the test board by the i	eflow.	The test samples shall be soldered to the test board by the reflow.				
	The test	samples shall be placed	I at specified temperatu	re for	The test samples shall be placed at specified temperature for				
	specified	specified time by step 1 to step 4 as shown in below table in				specified time by step 1 to step 4 as shown in below table in			
	sequence. The temperature cycle shall be repeated 100 cycles.				sequence. The temperature cycle shall be repeated 100 cycles.				
To at Matheada		Conditions of 1 cycle				Conditions of 1 cycle			
Test Methods and Remarks	Step	Temperature (°C)	Duration (min)		Step	Temperature (°C)	Duration (min)		
	1	$-40 \pm 3$	$30\pm3$		1	$-40 \pm 3$	30±3		
	2	Room temperature	Within 3		2	Room temperature	Within 3		
	3	$+85\pm2$	$30\pm3$		3	$+125\pm2$	30±3		
	4	Room temperature	Within 3		4	Room temperature	Within 3		
	Recovery : At least 2hrs of recovery under the standard condition				Recovery : At least 2hrs of recovery under the standard condition				
	after the test, followed by the measurement within 48hrs.				after the test, followed by the measurement within 48hrs.				

17. Damp heat						
Specified Value	Inductance change : Within $\pm$ 10% No significant abnormality in appearance.					
	LSBH/LLBH:			LSBH/LLBH (125°	C guaranteed product):	
	The test samples shall be soldered to the test board by the reflow.			The test samples shall be soldered to the test board by the reflow.		
				The test samples shall be placed in thermostatic oven set at		
Test Methods				specified temperature and humidity as shown in below table.		
and Remarks	Temperature	60±2°C		Temperature	85±2°C	
	Humidity	90~95%RH		Humidity	85%RH	
	Time	1000+24/-0 hour		Time	1000+24/-0 hour	
	Recovery : At least 2hrs of recovery under the standard condition			Recovery : At least 2hrs of recovery under the standard condition		
	after the test, followed by the measurement within 48hrs.			after the test, follo	wed by the measurement wi	thin 48hrs.

18. Loading under	damp heat					
Specified Value	Inductance change : Within $\pm 10\%$ No significant abnormality in appearance.					
	LSBH/LLBH: The test samples shall be soldered to the test board by the reflow. The test samples shall be placed in thermostatic oven set at			LSBH/LLBH (125°C guaranteed product): The test samples shall be soldered to the test board by the reflow. The test samples shall be placed in thermostatic oven set at		
Test Methods	specified temperature and humidity and applied the rated current continuously as shown in below table.			specified temperature and humidity and applied the rated current continuously as shown in below table.		
and Remarks	Temperature	60±2°C		Temperature	85±2°C	
	Humidity	90~95%RH		Humidity	85%RH	
	Applied current	Rated current		Applied current	Rated current	
	Time	1000+24/-0 hour		Time	1000+24/-0 hour	
	Recovery : At least 2hrs of recovery under the standard condition			Recovery : At least 2hrs of recovery under the standard condition		
	after the test, followed by the measurement within 48hrs.			after the test, follow	ed by the measurement w	ithin 48hrs.

19. Low temperatur	e life test				
Specified Value	Inductance change : Within $\pm$ 10% No significant abnormality in appearance.				
Test Methods	board by the reflow. After that, the test samples shall be placed at test conditions as shown				
and Remarks	Temperature	-40±2°C			
	Time	1000+24/-0 hour			
	Recovery : At least 2	hrs of recovery under the	standard condition after the test. followed by the measurement within 48hrs.		



20. High temperatur	re life test			
Specified Value	Inductance change : Within $\pm 10\%$ No significant abnormality in appearance.			
Test Methods	The test samples s in below table.	hall be soldered to the test	board by the reflow. After that, the test samples shall be placed at test conditions as shown	
and Remarks	Temperature	85±2°C		
	Time	1000 + 24 / -0 hour		
	Recovery : At least	2hrs of recovery under the	e standard condition after the test, followed by the measurement within 48hrs.	

21. Loading at high temperature life test			
Specified Value	-		
Specified Value	-		

22. Standard condit	ion
Specified Value	Standard test condition : Unless otherwise specified, temperature is 20±15°C and 65±20% of relative humidity. When there is any question concerning measurement result: In order to provide correlation data, the test shall be condition of 20±2°C of temperature, 65±5% relative humidity. Inductance is in accordance with our measured value.